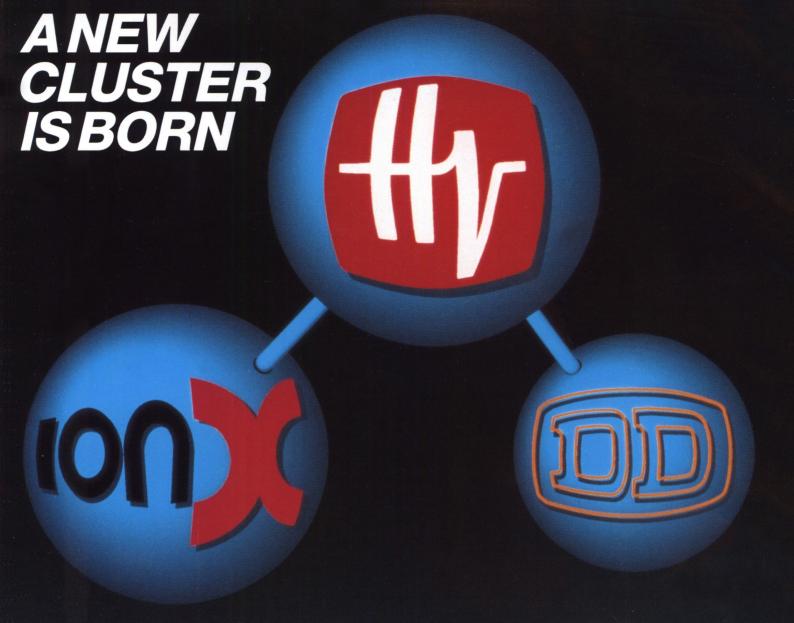
MRS BULLETIN

September 1989

Volume XIV, Number 9

Serving the International Materials Research Community





General Ionex acquired by High Voltage Engineering Europa B.V.

In December 1987 High Voltage Engineering Europa B.V. (HVEE) acquired Dowlish Developments Ltd (DD), an accelerator tube manufacturer located in the United Kingdom.

On April 10, 1989, HVEE purchased the General Ionex Analytical Product Group from Genus Inc. based in the United States.

Through this acquisition HVEE positions itself as the largest and most diverse manufacturer of particle accelerators for the scientific and industrial research communities.

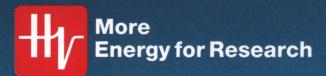
The acquired General Ionex (GI) product lines, which include the Tandetron accelerator systems and Model 4175 RBS Analyser, will be manufactured in HVEE's new, well-equipped facility in Amersfoort, The Netherlands.

World wide marketing of all products from HVEE, DD and GI will originate from HVEE Amersfoort with sales and service offices in the USA, Europe and Japan.

After addition of the newly acquired products HVEE's product lines include:

- Ion Accelerator Systems
 - Air insulated accelerators up to 500 kV
 - Single ended Van de Graaff accelerators up to 4 MV
 - Tandem Tandetron accelerators up to 3 MV/TV
- Research ion implanters
 - Beam energies 10 keV-9 MeV and higher
- Systems for ion beam analysis
 - Systems for RBS, PIXE, PIGE, NRA, ERD, MACS and MEIS
- Components
 - HV power supplies, electron and ion accelerator tubes, ion sources beamline components, beam monitoring equipment, UHV sample manipulators, etc.

For further information on this transaction and product literature please contact HVEE in Amersfoort/NL.



HIGH VOLTAGE ENGINEERING EUROPA B.V.

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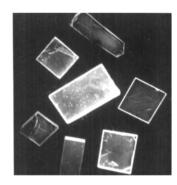
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ON THE COVER: Luminescence from crystals of Cu-doped and β "-alumina under ultraviolet excitation. The Cu- emission is "tuned" to different wavelengths by using codopants which alter the c-axis lattice parameter. The results are further described in "Frontiers in β "-Alumina Research" by B. Dunn, G.C. Farrington, and J.O. Thomas beginning on p. 22. Photo: C.H. Barrie Jr.

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The Society's interdisciplinary approach to the exchange of technical information is qualitatively different from that provided by singlediscipline professional societies because it promotes technical exchange across the various fields of science affecting materials development. MRS sponsors two major international annual meetings encompassing approximately 30 topical symposia, as well as numerous

single-topic scientific meetings each year. It recognizes professional and technical excellence, conducts short courses, and fosters technical exchange in various local geographic regions through Section activities and Student Chapters on university campuses.

MRS is an Affiliated Society of the American Institute of Physics and participates in the international arena of materials research through associations with professional organizations such as European MRS.

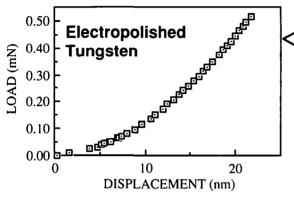
MRS publishes symposia proceedings, the MRS BULLETIN, Journal of Materials Research, and other current scientific developments.

For further information on the Society's activities, contact MRS Headquarters, 9800 McKnight Road, Suite 327, Pittsburgh, Pennsylvania 15237; telephone (412) 367-3003; facsimile (412) 367-4373.

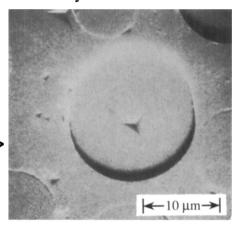
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